

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 09.0027
CB Certificate No.: 20004520 ITL

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Appendix-1 (20004520 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Electrical Analysis (IV-curve tracer, TDR, Probing test, Electric meter, Isolation test, Open/short test, Auto curve tracer, Network analyzer, Module product analysis test, Power supply test, Thermal emission test, OBIRCH test, LCR meter, Oscilloscope)	AFOP-02, AFOP-03, AFOP-04, AFOP-05, AFOP-16, AFOP-17, AFOP-21, AFOP-22, AFOP-24, AFOP-26, AFOP-29, AFOP-30, AFQP-34, AFOP-37
Physical Analysis (Chemical etch test, High/Low-power microscope, Laser de-cap, Chemical de-cap, Molding /Grinding /Polishing /Cutting test, PECS test, SAT test, 2D/3D CT X-ray, RIE, Ion milling, PFIB, X-RADIA CT X-ray, SEM&EDX, Laser marking, IR microscope)	AFOP-01, AFOP-06, AFOP-10, AFOP-12, AFOP-13, AFOP-15, AFOP-18, AFOP-19, AFOP-23, AFOP-25, AFOP-27, AFOP-28, AFOP-31, AFOP-35, AFOP-36

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